

SN54LVT543, SN74LVT543 3.3-V ABT OCTAL REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS137D – MAY 1992 – REVISED JULY 1995

- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static Power Dissipation
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Bus-Hold Data Inputs Eliminate the Need for External Pullup Resistors
- Support Live Insertion
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), and Ceramic (JT) DIPs

description

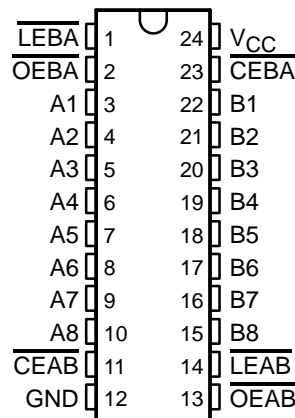
These octal transceivers are designed specifically for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

The 'LVT543 contain two sets of D-type latches for temporary storage of data flowing in either direction. Separate latch-enable (\overline{LEAB} or \overline{LEBA}) and output-enable (\overline{OEAB} or \overline{OEBA}) inputs are provided for each register to permit independent control in either direction of data flow.

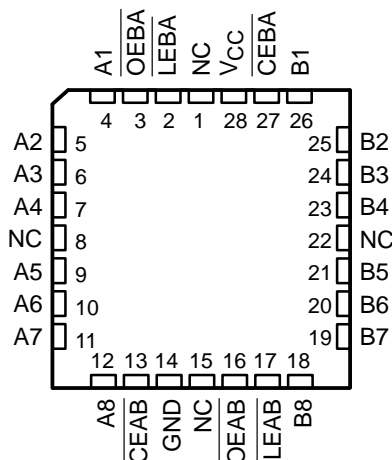
The A-to-B enable (\overline{CEAB}) input must be low in order to enter data from A or to output data from B. If \overline{CEAB} is low and \overline{LEAB} is low, the A-to-B latches are transparent; a subsequent low-to-high transition of \overline{LEAB} puts the A latches in the storage mode. With \overline{CEAB} and \overline{OEAB} both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar but requires using the \overline{CEBA} , \overline{LEBA} , and \overline{OEBA} inputs.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

SN54LVT543 . . . JT PACKAGE
SN74LVT543 . . . DB, DW, OR PW PACKAGE
(TOP VIEW)



SN54LVT543 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection



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description (continued)

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVT543 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN54LVT543 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74LVT543 is characterized for operation from -40°C to 85°C .

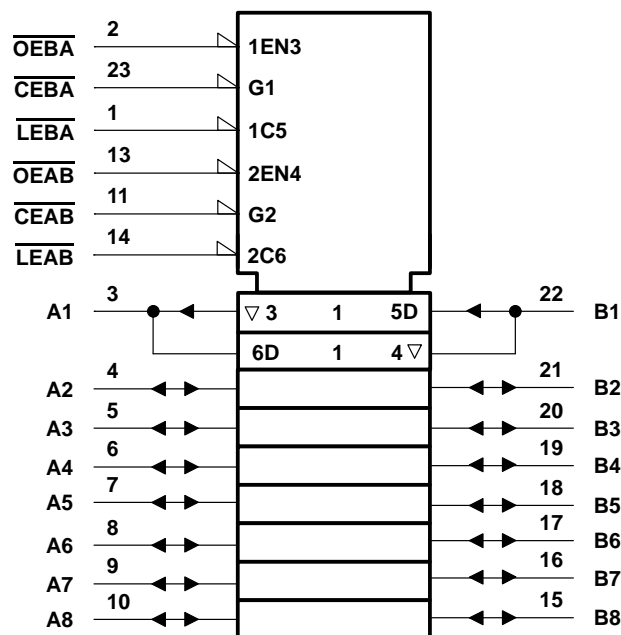
FUNCTION TABLE†

INPUTS				OUTPUT B
\overline{CEAB}	\overline{LEAB}	\overline{OEAB}	A	
H	X	X	X	Z
X	X	H	X	Z
L	H	L	X	B_0^{\ddagger}
L	L	L	L	L
L	L	L	H	H

† A-to-B data flow is shown; B-to-A flow control is the same except that it uses \overline{CEBA} , \overline{LEBA} , and \overline{OEBA} .

‡ Output level before the indicated steady-state input conditions were established

logic symbol§



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DB, DW, JT, and PW packages.

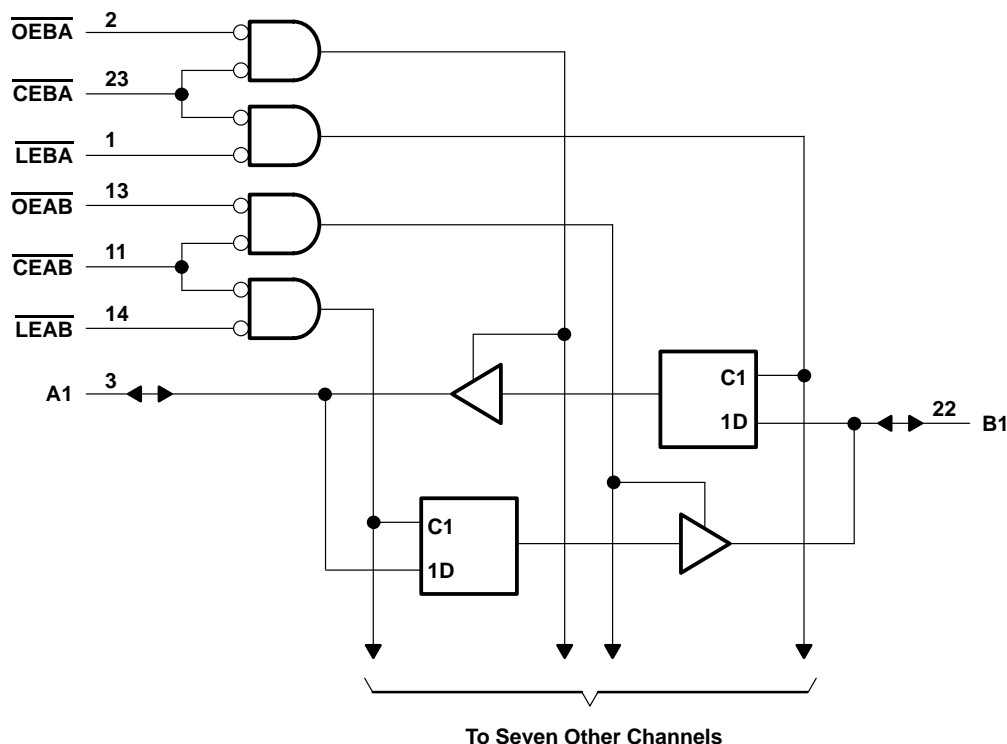
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logic diagram (positive logic)



Pin numbers shown are for the DB, DW, JT, and PW packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O (see Note 1)	–0.5 V to 7 V
Current into any output in the low state, I_O : SN54LVT543	96 mA
SN74LVT543	128 mA
Current into any output in the high state, I_O (see Note 2): SN54LVT543	48 mA
SN74LVT543	64 mA
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 3): DB package	0.65 W
DW package	1.7 W
PW package	0.7 W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.



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recommended operating conditions (see Note 4)

			SN54LVT543		SN74LVT543		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage		2.7	3.6	2.7	3.6	V
V _{IH}	High-level input voltage		2		2		V
V _{IL}	Low-level input voltage			0.8		0.8	V
V _I	Input voltage			5.5		5.5	V
I _{OH}	High-level output current			–24		–32	mA
I _{OL}	Low-level output current			48		64	mA
Δt/Δv	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
T _A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54LVT543			SN74LVT543			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = 2.7\text{ V}$, $I_I = -18\text{ mA}$				-1.2			-1.2	V
V_{OH}	$V_{CC} = \text{MIN to MAX}^\ddagger$, $I_{OH} = -100\text{ }\mu\text{A}$		$V_{CC}-0.2$			$V_{CC}-0.2$			V
	$V_{CC} = 2.7\text{ V}$, $I_{OH} = -8\text{ mA}$		2.4			2.4			
	$V_{CC} = 3\text{ V}$	$I_{OH} = -24\text{ mA}$	2						
		$I_{OH} = -32\text{ mA}$				2			
V_{OL}	$V_{CC} = 2.7\text{ V}$	$I_{OL} = 100\text{ }\mu\text{A}$			0.2			0.2	V
		$I_{OL} = 24\text{ mA}$			0.5			0.5	
	$V_{CC} = 3\text{ V}$	$I_{OL} = 16\text{ mA}$			0.4			0.4	
		$I_{OL} = 32\text{ mA}$			0.5			0.5	
		$I_{OL} = 48\text{ mA}$			0.55				
		$I_{OL} = 64\text{ mA}$						0.55	
I_I	$V_{CC} = 3.6\text{ V}$, $V_I = V_{CC}\text{ or GND}$	Control inputs			± 1			± 1	μA
	$V_{CC} = 0\text{ or MAX}^\ddagger$, $V_I = 5.5\text{ V}$				10			10	
	$V_{CC} = 3.6\text{ V}$	$V_I = 5.5\text{ V}$			20			20	
		$V_I = V_{CC}$			5			5	
		$V_I = 0$			-10			-10	
I_{off}	$V_{CC} = 0$, $V_I\text{ or }V_O = 0\text{ to }4.5\text{ V}$							± 100	μA
$I_{I(\text{hold})}$	$V_{CC} = 3\text{ V}$	$V_I = 0.8\text{ V}$	A or B ports		75			75	μA
		$V_I = 2\text{ V}$			-75			-75	
I_{OZH}	$V_{CC} = 3.6\text{ V}$, $V_O = 3\text{ V}$				1			1	μA
I_{OZL}	$V_{CC} = 3.6\text{ V}$, $V_O = 0.5\text{ V}$				-1			-1	μA
I_{CC}	$V_{CC} = 3.6\text{ V}$, $V_I = V_{CC}\text{ or GND}$, $I_O = 0$	Outputs high		0.13	0.19		0.13	0.19	mA
		Outputs low		8.8	12		8.8	12	
		Outputs disabled		0.13	0.19		0.13	0.19	
ΔI_{CC}^\P	$V_{CC} = 3\text{ V to }3.6\text{ V}$, One input at $V_{CC} - 0.6\text{ V}$, Other inputs at $V_{CC}\text{ or GND}$				0.2			0.2	mA
C_i	$V_I = 3\text{ V or }0$				4.5			4.5	pF
C_{io}	$V_O = 3\text{ V or }0$				11			11	pF

† All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

§ Unused terminals at V_{CC} or GND

¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

				SN54LVT543				SN74LVT543				UNIT
				$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t_W	Pulse duration,	\overline{LEAB} or \overline{LEBA} low		3.3		3.3		3.3		3.3		ns
t_{su}	Setup time	A or B before \overline{LEAB} or $\overline{LEBA}\uparrow$		Data high	0		0		0		0	ns
				Data low	0.8		1.1		0.8		1.1	
		A or B before \overline{CEAB} or $\overline{CEBA}\uparrow$		Data high	0		0		0		0	
				Data low	0.9		1.2		0.9		1.2	
t_h	Hold time	A or B after \overline{LEAB} or $\overline{LEBA}\uparrow$			1.7		1.7		1.7		1.7	ns
		A or B after \overline{CEAB} or $\overline{CEBA}\uparrow$			1.8		1.8		1.8		1.8	

switching characteristics over recommended operating free-air temperature range, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVT543				SN74LVT543				UNIT	
			V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V			
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN		MAX
t _{PLH}	A or B	B or A	1	4.9	5.7		1	2.9	4.7	5.5		ns
t _{PHL}			1	4.8	6		1	3.3	4.6	5.8		
t _{PLH}	\overline{LE}	A or B	1	6.1	7.5		1	4	5.9	7.3		ns
t _{PHL}			1	5.9	7.5		1	4.1	5.7	7.3		
t _{PZH}	\overline{OE}	A or B	1	6	7.8		1	4.1	5.8	7.6		ns
t _{PZL}			1.1	6.6	8.4		1.1	4.5	6.4	8.2		
t _{PHZ}	\overline{OE}	A or B	2.4	6.7	7.3		2.4	4.8	6.5	7.1		ns
t _{PLZ}			2	6	6.1		2	4	5.8	5.9		
t _{PZH}	\overline{CE}	A or B	1	6.2	7.8		1	4.2	6	7.6		ns
t _{PZL}			1.4	6.9	8.5		1.4	4.7	6.7	8.3		
t _{PHZ}	\overline{CE}	A or B	2.3	6.6	7.3		2.3	4.7	6.4	7.1		ns
t _{PLZ}			2	5.6	5.8		2	3.8	5.4	5.6		

† All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

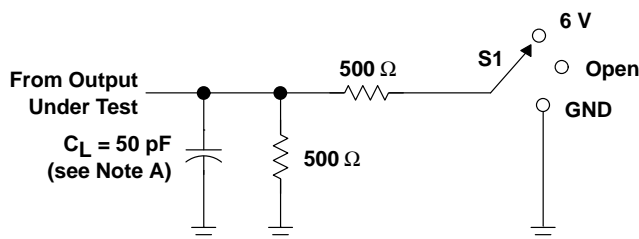
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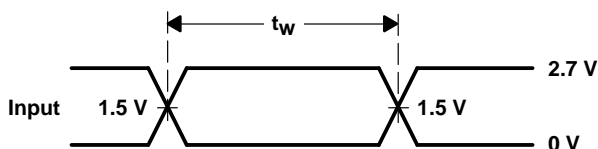
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PARAMETER MEASUREMENT INFORMATION

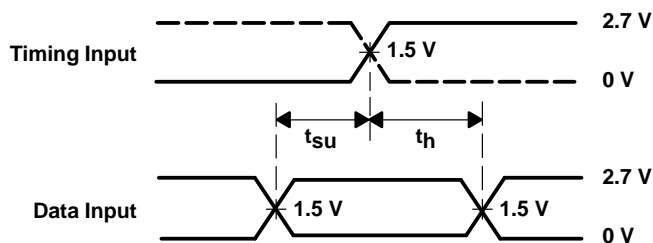


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND

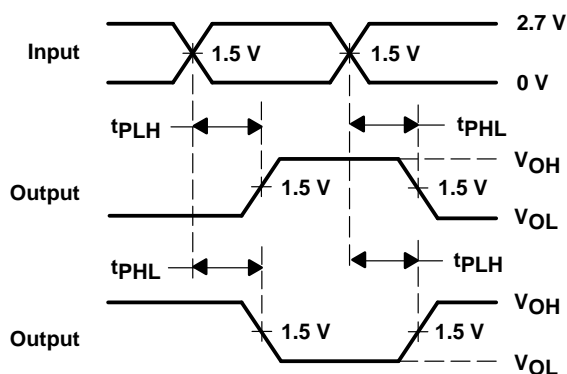
LOAD CIRCUIT FOR OUTPUTS



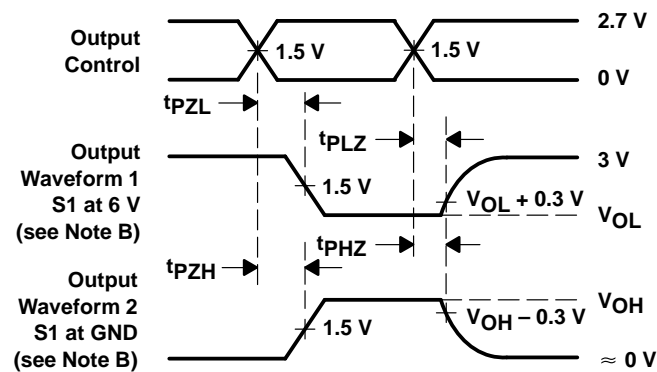
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
 - The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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